

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/773,640	CHEN ET AL.	
Examiner	Art Unit	
PHUC H. TRAN	2616	

	SEAR	CHED	
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East search see history	7/21/2008	P.T		